

Special Issue

Frequency Comb for Precise Measurement

Message from the Guest Editor

Optical frequency combs have revolutionized optical frequency metrology and precision measurement since its invention more than ten years ago. They have made it possible to directly link the optical frequency to microwave frequency, and thus they have been applied for precision measurements of fundamental constants, and high-precision atomic clocks.

Now optical frequency combs have been widely used in various applications including optical and microwave frequency synthesis, attosecond pulse generation, direct frequency comb spectroscopy, and precision distance measurements. In this special issue, we focus on optical frequency combs and related technologies for precise measurement and also the various applications based on optical frequency combs.

Guest Editor

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As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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